

APR 08 2004

<p>Form PTO-1449 <b>INFORMATION DISCLOSURE STATEMENT IN AN APPLICATION</b> <i>(Use several sheets if necessary)</i></p>	Docket Number 416272004201		Application Number 10/729,726
	Applicant Sung-Mo KANG and Seung-Moon YOO		
	Filing Date December 5, 2003	Group Art Unit 2838 2816	
	Mailing Date April 5, 2004		

**U.S. PATENT DOCUMENTS**

Examiner Initials	Ref. No.	Date	Document No.	Name	Class	Subclass	Filing Date If Appropriate
JZ	1.	5/19/1992	5,115,150	Ludwig, Mark A.	—	—	
see PTO-892	2.	9/29/1992	5,151,620	Lin, Ming-Zen	—	—	
JZ	3.	12/29/1992	5,175,448	Fujii	—	—	
JZ	4.	8/26/1997	5,661,419	Bhagwan	—	—	
892	5.	3/9/1999	5,880,604	Kawahara et al.	—	—	
see PTO-892	6.	4/11/2000	6,049,245	Sen et al.	—	—	
892	7.	8/22/2000	6,107,869	Horiguchi et al.	—	—	
892	8.	2/20/2001	6,191,615	Koga, Hiroshi	—	—	
JZ	9.	3/20/2001	6,204,696	Krishnamurthy et al.	—	—	
JZ	10.	4/9/2002	6,370,052 B1	Hsu et al.	—	—	
892	11.	6/11/2002	6,404,269	Voldman	—	—	
892	12.	6/25/2002	6,411,157	Hsu et al.	—	—	
JZ	13.	8/27/2002	6,442,086 B1	Dean	—	—	
JZ	14.	12/2002	6,492,837 B1	Narendra et al.	—	—	
JZ	15.	5/21/2002	10/153,158	Yoo et al.	—	—	

**FOREIGN PATENT DOCUMENTS**

Examiner Initials	Ref. No.	Date	Document No.	Country	Class	Subclass	Translation YES NO

**OTHER DOCUMENTS**

*(including author, title, Date, Pertinent Pages, Etc.)*

Examiner Initials	Ref. No.	Title
JZ	16.	M. Anis et al., "Dynamic and Leakage Power Reduction in MTCMOS Circuits Using an Automated Efficient Gate Clustering Technique", IEEE, June 10-14, 2002, New Orleans, Louisiana, pp. 480-485.
JZ	17.	Assaderaghi et al., "A Dynamic Threshold Voltage MOSFET (DTMOS) for Ultra-Low

EXAMINER: *Jeffrey Zweizig* DATE CONSIDERED: *11/22/04*

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~~x did not receive~~

Form PTO-1449		Docket Number 416272004201	Application Number 10/729,726
INFORMATION DISCLOSURE CITATION IN AN APPLICATION		Applicant Sung-Mo KANG and Seung-Moon YOO	
(Use several sheets if necessary)		Filing Date December 5, 2003	Group Art Unit 2838
		Mailing Date April 5, 2004	

<i>cont</i>		Voltage Operation", <i>International Electron Devices Meeting, Digest of Technical Papers</i> , pages 809-812, June 1994.
<i>JZ</i>	18.	J. Burr and J. Scott, "A 200mV Self-Testing Encoder/Decoder using Stanford Ultra-Low-Power CMOS", <i>ISSCC Digest of Technical Papers</i> , pages 84-85, February 1994.
<i>JZ</i>	19.	Mark N. Horenstein, <i>Microelectronic Circuits &amp; Devices</i> , 1996, pgs. 240-250.
<i>JZ</i>	20.	M. Horiguchi et al., "Switched-Source-Impedance CMOS Circuit for Low Standby Subthreshold Current Giga-Scale LSI's", <i>IEEE Journal of Solid State Circuits</i> , 28(11):1131-1135, November 1993.
<i>JZ</i>	21.	T. Iwata et al., "Gate-Over-Driving CMOS Architecture for 0.5V Single-Power-Supply-Operated Devices", <i>ISSCC Digest of Technical Papers</i> , pages 290-291, February 1997.
<i>JZ</i>	22.	Kawaguchi et al., "A CMOS Scheme for 0.5V Supply Voltage with Pico-Ampere Standby Current", <i>ISSCC Digest of Technical Papers</i> , pages 192-193, February 1998.
<i>JZ</i>	23.	T. Kuroda et al., "A 0.9V 150MHz 10mW 4mm <sup>2</sup> 2D Discrete Cosine Transform Core Processor with Variable-Threshold-Voltage Scheme", <i>ISSCC Digest of Technical Papers</i> , pages 166-167, February 1996.
<i>JZ</i>	24.	Mutoh et al., "1-V Power Supply High-Speed Digital Circuit Technology with Multithreshold-Voltage CMOS", <i>IEEE Journal of Solid State Circuits</i> , 30(8): 845-854, August 1995.
<i>JZ</i>	25.	K. Seta et al., "50% Active-Power Saving without Speed Degradation Using Standby Power Reduction (SPR) Circuit", in <i>ISSCC Digest of Technical Papers</i> , pages 318-319, February 1995.
<i>JZ</i>	26.	S. Shigematsu et al., "A 1-V High-Speed MTCMOS Circuit Scheme for Power-Down Application Circuits", <i>IEEE Journal of Solid State Circuits</i> , 32(6):861-869, June 1997.
<i>JZ</i>	27.	Seung-Moon Yoo et al., "New High Performance Sub-1V Circuit Technique with Reduced Standby Current and Robust Data Holding", <i>IEEE International Symposium on Circuits and Systems</i> , May 28-31, 2000, Geneva, Switzerland (Pages 1-4)
<i>considered but</i>	28.	Notice of Allowance and Fee due, Notice of Allowability and Examiner's Amendment for Application Ser. no. 10/153,158, 6 pgs.
<i>not printed</i>	29.	Amendment A for the U. S. patent application 10/153,158, Yoo et al., filed 5/21/2002, 13 pgs. 4/9/2003.
<i>JZ</i>	30.	International Search Report mailed on February 25, 2004, for PCT/US03/24976 filed on August 8, 2003, 7 pgs.

\* ~~Disc~~ ~~not recd~~

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ALTERNATIVE TO PTO/SB/062/b (08-03)

Substitute for Form 1449/PTO				Complete if Known	
				Application Number	10/729,726
				Filing Date	December 5, 2003
				First Named Inventor	Sung-Mo KANG
				Art Unit	2816
				Examiner Name	J. S. Zweizig
Sheet	1	of	1	Attorney Docket Number	416272004201

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No.*	Document Number Number-Kind Code <sup>2</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
JZ	1.	6,759,873	7/6/2004	Kang et al.	

FOREIGN PATENT DOCUMENTS					
Examiner Initials*	Cite No.*	Foreign Patent Document Country Code <sup>1</sup> -Number-Kind Code <sup>2</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
					T <sup>3</sup>

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NON PATENT LITERATURE DOCUMENTS					
Examiner Initials*	Cite No.*	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.			

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<sup>1</sup>Applicant's unique citation designation number (optional). <sup>2</sup>Applicant is to place a check mark here if English language Translation is attached.

Examiner Signature 6-1819144	Jeffrey Zweizig	Date Considered	11/22/04
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